# imall

Chipsmall Limited consists of a professional team with an average of over 10 year of expertise in the distribution of electronic components. Based in Hongkong, we have already established firm and mutual-benefit business relationships with customers from, Europe, America and south Asia, supplying obsolete and hard-to-find components to meet their specific needs.

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### **FEATURES**

- 72.8dB SNR
- 88dB SFDR
- Low Power: 149mW
- Single 1.8V Supply
- CMOS, DDR CMOS or DDR LVDS Outputs
- Selectable Input Ranges: 1V<sub>P-P</sub> to 2V<sub>P-P</sub>
- 800MHz Full-Power Bandwidth S/H
- Optional Data Output Randomizer
- Optional Clock Duty Cycle Stabilizer
- Shutdown and Nap Modes
- Serial SPI Port for Configuration
- Pin Compatible 14-Bit and 12-Bit Versions
- 40-Pin ( $6mm \times 6mm$ ) QFN Package

### **APPLICATIONS**

- Communications
- Cellular Base Stations
- Software Defined Radios
- Portable Medical Imaging
- Multi-Channel Data Acquisition
- Nondestructive Testing

# LTC2262-14 14-Bit, 150Msps Ultralow Power 1.8V ADC

### DESCRIPTION

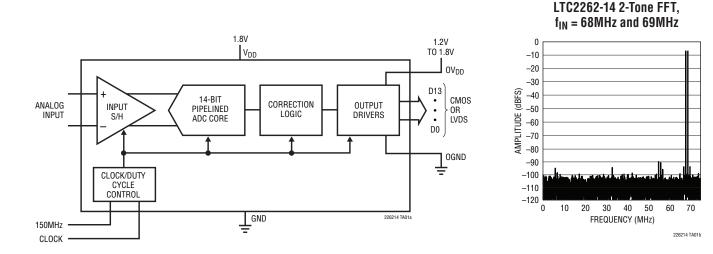
The LTC<sup>®</sup>2262-14 is a sampling 14-bit A/D converter designed for digitizing high frequency, wide dynamic range signals. The LTC2262-14 is perfect for demanding communications applications with AC performance that includes 72.8dB SNR and 88dB spurious free dynamic range (SFDR). Ultralow jitter of 0.17ps<sub>BMS</sub> allows undersampling of IF frequencies with excellent noise performance.

DC specs include ±1LSB INL (typical), ±0.3LSB DNL (typical) and no missing codes over temperature. The transition noise is a low 1.2LSB<sub>BMS</sub>.

The digital outputs can be either full rate CMOS, double data rate CMOS, or double data rate LVDS. A separate output power supply allows the CMOS output swing to range from 1.2V to 1.8V.

The ENC<sup>+</sup> and ENC<sup>-</sup> inputs may be driven differentially or single ended with a sine wave, PECL, LVDS, TTL or CMOS inputs. An optional clock duty cycle stabilizer allows high performance at full speed for a wide range of clock duty cycles.

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### TYPICAL APPLICATION



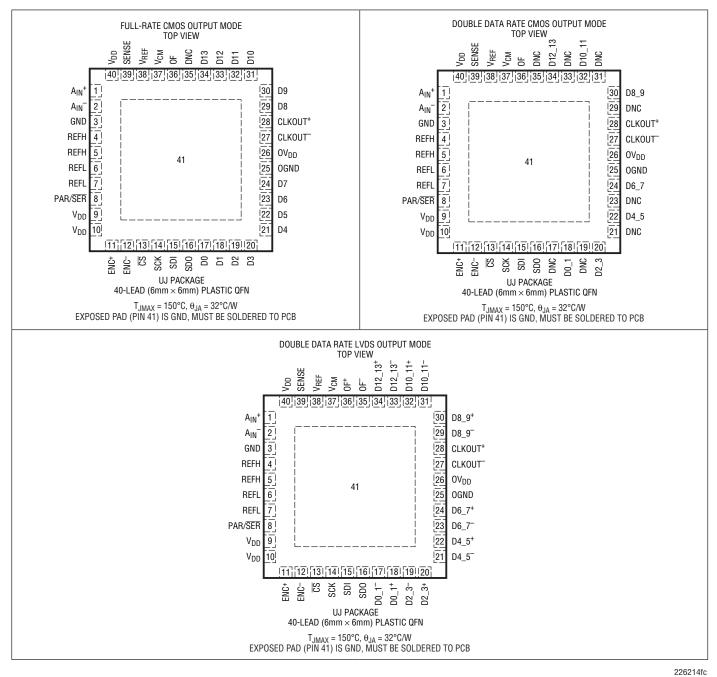


### ABSOLUTE MAXIMUM RATINGS (Notes 1, 2)

Supply Voltages (V <sub>DD</sub> , OV <sub>DD</sub> )0.3V to 2	V
Analog Input Voltage (A <sub>IN</sub> <sup>+</sup> , A <sub>IN</sub> <sup>-</sup> ,	
PAR/SER, SENSE) (Note 3)0.3V to (V <sub>DD</sub> + 0.2V	/)
Digital Input Voltage (ENC <sup>+</sup> , ENC <sup>-</sup> , CS,	
SDI, SCK) (Note 4)0.3V to 3.9	V
SDO (Note 4)0.3V to 3.9	V

Digital Output Voltage	–0.3V to (OV <sub>DD</sub> + 0.3V)
Operating Temperature Range:	
LTC2262C	0°C to 70°C
LTC22621	–40°C to 85°C
Storage Temperature Range	65°C to 150°C

### PIN CONFIGURATIONS





### **ORDER INFORMATION**

LEAD FREE FINISH	TAPE AND REEL	PART MARKING*	PACKAGE DESCRIPTION	TEMPERATURE RANGE
LTC2262CUJ-14#PBF	LTC2262CUJ-14#TRPBF	LTC2262UJ-14	40-Lead (6mm $\times$ 6mm) Plastic QFN	0°C to 70°C
LTC2262IUJ-14#PBF	LTC2262IUJ-14#TRPBF	LTC2262UJ-14	40-Lead (6mm $\times$ 6mm) Plastic QFN	-40°C to 85°C

Consult LTC Marketing for parts specified with wider operating temperature ranges. \*The temperature grade is identified by a label on the shipping container. Consult LTC Marketing for information on non-standard lead based finish parts.

For more information on lead free part marking, go to: http://www.linear.com/leadfree/

For more information on tape and reel specifications, go to: http://www.linear.com/tapeandreel/

## **CONVERTER CHARACTERISTICS** The $\bullet$ denotes the specifications which apply over the full operating temperature range, otherwise specifications are at T<sub>A</sub> = 25°C. (Note 5)

PARAMETER	CONDITIONS		MIN	ТҮР	MAX	UNITS
Resolution (No Missing Codes)		•	14			Bits
Integral Linearity Error	Differential Analog Input (Note 6)	•	-4	±1	4	LSB
Differential Linearity Error	Differential Analog Input	•	-1	±0.3	1	LSB
Offset Error	(Note 7)	•	-9	±1.5	9	mV
Gain Error	Internal Reference External Reference	•	-1.5	±1.5 ±0.4	1.5	%FS %FS
Offset Drift				±20		μV/°C
Full-Scale Drift	Internal Reference External Reference			±30 ±10		ppm/°C ppm/°C
Transition Noise	External Reference			1.2		LSB <sub>RMS</sub>

#### **ANALOG INPUT** The • denotes the specifications which apply over the full operating temperature range, otherwise specifications are at $T_A = 25$ °C. (Note 5)

SYMBOL	PARAMETER	CONDITIONS		MIN	ТҮР	МАХ	UNITS
V <sub>IN</sub>	Analog Input Range $(A_{IN}^+ - A_{IN}^-)$	1.7V < V <sub>DD</sub> < 1.9V	•		1 to 2		V <sub>P-P</sub>
V <sub>IN(CM)</sub>	Analog Input Common Mode $(A_{IN}^{+} + A_{IN}^{-})/2$	Differential Analog Input (Note 8)	٠	V <sub>CM</sub> – 100mV	V <sub>CM</sub>	V <sub>CM</sub> + 100mV	V
V <sub>SENSE</sub>	External Voltage Reference Applied to SENSE	External Reference Mode	٠	0.625	1.250	1.300	V
IINCM	Analog Input Common Mode Current	Per Pin, 150Msps			185		μA
I <sub>IN1</sub>	Analog Input Leakage Current	$0 < A_{IN}^+$ , $A_{IN}^- < V_{DD}$ , No Encode	٠	-1		1	μA
I <sub>IN2</sub>	PAR/SER Input Leakage Current	$0 < PAR/\overline{SER} < V_{DD}$	٠	-3		3	μA
I <sub>IN3</sub>	SENSE Input Leakage Current	0.625 < SENSE < 1.3V	٠	-6		6	μA
t <sub>AP</sub>	Sample-and-Hold Acquisition Delay Time				0		ns
t <sub>JITTER</sub>	Sample-and-Hold Acquisition Delay Jitter				0.17		ps <sub>RMS</sub>
CMRR	Analog Input Common Mode Rejection Ratio				80		dB
BW-3B	Full-Power Bandwidth	Figure 6 Test Circuit			800		MHz



**DYNAMIC ACCURACY** The  $\bullet$  denotes the specifications which apply over the full operating temperature range, otherwise specifications are at T<sub>A</sub> = 25°C. A<sub>IN</sub> = -1dBFS. (Note 5)

SYMBOL	PARAMETER	CONDITIONS		MIN	ТҮР	MAX	UNITS
SNR	Signal-to-Noise Ratio	5MHz Input 30MHz Input 70MHz Input 140MHz Input	•	70.4	72.8 72.7 72.5 72.1		dB dB dB dB
SFDR	Spurious Free Dynamic Range 2nd or 3rd Harmonic	5MHz Input 30MHz Input 70MHz Input 140MHz Input	•	74	88 88 82 81		dB dB dB dB
	Spurious Free Dynamic Range 4th Harmonic or Higher	5MHz Input 30MHz Input 70MHz Input 140MHz Input			90 90 90 90		dB dB dB dB
S/(N+D)	Signal-to-Noise Plus Distortion Ratio	5MHz Input 30MHz Input 70MHz Input 140MHz Input	•	69.3	72.7 72.5 72 71.6		dB dB dB dB

## **INTERNAL REFERENCE CHARACTERISTICS** The $\bullet$ denotes the specifications which apply over the full operating temperature range, otherwise specifications are at T<sub>A</sub> = 25°C. (Note 5)

PARAMETER	CONDITIONS	MIN	ТҮР	МАХ	UNITS
V <sub>CM</sub> Output Voltage	$I_{OUT} = 0$	0.5 • V <sub>DD</sub> – 25mV	0.5 • V <sub>DD</sub>	0.5 • V <sub>DD</sub> + 25mV	V
V <sub>CM</sub> Output Temperature Drift			±25		ppm/°C
V <sub>CM</sub> Output Resistance	–600μA < I <sub>OUT</sub> < 1mA		4		Ω
V <sub>REF</sub> Output Voltage	I <sub>OUT</sub> = 0	1.225	1.250	1.275	V
V <sub>REF</sub> Output Temperature Drift			±25		ppm/°C
V <sub>REF</sub> Output Resistance	-400μA < I <sub>OUT</sub> < 1mA		7		Ω
V <sub>REF</sub> Line Regulation	1.7V < V <sub>DD</sub> < 1.9V		0.6		mV/V

## **DIGITAL INPUTS AND OUTPUTS** The $\bullet$ denotes the specifications which apply over the full operating temperature range, otherwise specifications are at T<sub>A</sub> = 25°C. (Note 5)

SYMBOL	PARAMETER	CONDITIONS		MIN	ТҮР	MAX	UNITS
ENCODE	INPUTS (ENC <sup>+</sup> , ENC <sup>-</sup> )	I					
Differenti	ial Encode Mode (ENC <sup>-</sup> Not Tied to GN	ID)					
V <sub>ID</sub>	Differential Input Voltage	(Note 8)	•	0.2			V
V <sub>ICM</sub>	Common Mode Input Voltage	Internally Set Externally Set (Note 8)	•	1.1	1.2	1.6	V V
VIN	Input Voltage Range	ENC <sup>+</sup> , ENC <sup>-</sup> to GND	•	0.2		3.6	V
R <sub>IN</sub>	Input Resistance	(See Figure 10)			10		kΩ
CIN	Input Capacitance	(Note 8)			3.5		pF
Single-Er	nded Encode Mode (ENC <sup></sup> Tied to GND	)					
VIH	High Level Input Voltage	V <sub>DD</sub> = 1.8V		1.2			V
V <sub>IL</sub>	Low Level Input Voltage	V <sub>DD</sub> = 1.8V	•			0.6	V
V <sub>IN</sub>	Input Voltage Range	ENC <sup>+</sup> to GND	•	0		3.6	V
R <sub>IN</sub>	Input Resistance	(See Figure 11)			30		kΩ
CIN	Input Capacitance	(Note 8)			3.5		pF





## **DIGITAL INPUTS AND OUTPUTS** The $\bullet$ denotes the specifications which apply over the full operating temperature range, otherwise specifications are at T<sub>A</sub> = 25°C. (Note 5)

SYMBOL	PARAMETER	CONDITIONS		MIN	ТҮР	MAX	UNITS
DIGITAL	INPUTS (CS, SDI, SCK)						
V <sub>IH</sub>	High Level Input Voltage	V <sub>DD</sub> = 1.8V		1.3			V
V <sub>IL</sub>	Low Level Input Voltage	V <sub>DD</sub> = 1.8V				0.6	V
I <sub>IN</sub>	Input Current	V <sub>IN</sub> = 0V to 3.6V	•	-10		10	μA
C <sub>IN</sub>	Input Capacitance	(Note 8)			3		pF
SDO OU	TPUT (Open-Drain Output. Requires 2k Pul	I-Up Resistor if SDO is Used)					
R <sub>OL</sub>	Logic Low Output Resistance to GND	V <sub>DD</sub> = 1.8V, SDO = 0V			200		Ω
I <sub>OH</sub>	Logic High Output Leakage Current	SD0 = 0V to 3.6V		-10		10	μA
C <sub>OUT</sub>	Output Capacitance	(Note 8)			4		pF
DIGITAL	DATA OUTPUTS (CMOS MODES: FULL DAT	A RATE AND DOUBLE DATA RATE)					
<b>OV<sub>DD</sub> =</b> 1	I.8V						
V <sub>OH</sub>	High Level Output Voltage	$I_0 = -500 \mu A$		1.750	1.790		V
V <sub>OL</sub>	Low Level Output Voltage	I <sub>0</sub> = 500μA			0.010	0.050	V
<b>OV<sub>DD</sub> =</b> 1	1.5V						
V <sub>OH</sub>	High Level Output Voltage	$I_0 = -500 \mu A$			1.488		V
V <sub>OL</sub>	Low Level Output Voltage	I <sub>0</sub> = 500μA			0.010		V
<b>OV<sub>DD</sub> =</b> 1	1.2V	·					
V <sub>OH</sub>	High Level Output Voltage	$I_0 = -500 \mu A$			1.185		V
V <sub>OL</sub>	Low Level Output Voltage	I <sub>0</sub> = 500μA			0.010		V
DIGITAL	DATA OUTPUTS (LVDS MODE)	· ·					
V <sub>OD</sub>	Differential Output Voltage	$100\Omega$ Differential Load, 3.5mA Mode $100\Omega$ Differential Load, 1.75mA Mode	•	247	350 175	454	mV mV
V <sub>OS</sub>	Common Mode Output Voltage	$100\Omega$ Differential Load, 3.5mA Mode $100\Omega$ Differential Load, 1.75mA Mode	•	1.125	1.250 1.250	1.375	V V
R <sub>TERM</sub>	On-Chip Termination Resistance	Termination Enabled, OV <sub>DD</sub> = 1.8V			100		Ω

## **POWER REQUIREMENTS** The $\bullet$ denotes the specifications which apply over the full operating temperature range, otherwise specifications are at T<sub>A</sub> = 25°C. (Note 9)

SYMBOL PARAMETER CONDITIONS MIN TYP MAX UNITS

CMOS O	utput Modes: Full Data Rate and I	Double Data Rate					
V <sub>DD</sub>	Analog Supply Voltage	(Note 10)		1.7	1.8	1.9	V
OV <sub>DD</sub>	Output Supply Voltage	(Note 10)		1.1		1.9	V
I <sub>VDD</sub>	Analog Supply Current	DC Input Sine Wave Input	•		82.7 84.5	95	mA mA
IOVDD	Digital Supply Current	Sine Wave Input, OV <sub>DD</sub> =1.2V			5.5		mA
P <sub>DISS</sub>	Power Dissipation	DC Input Sine Wave Input, OV <sub>DD</sub> =1.2V	•		149 159	171	mW mW



## **POWER REQUIREMENTS** The $\bullet$ denotes the specifications which apply over the full operating temperature range, otherwise specifications are at T<sub>A</sub> = 25°C. (Note 9)

SYMBOL	PARAMETER	CONDITIONS		MIN	ТҮР	MAX	UNITS
LVDS Outp	out Mode						
V <sub>DD</sub>	Analog Supply Voltage	(Note 10)	•	1.7	1.8	1.9	V
OV <sub>DD</sub>	Output Supply Voltage	(Note 10)	•	1.7		1.9	V
I <sub>VDD</sub>	Analog Supply Current	Sine Wave Input	•		88.1	101.3	mA
I <sub>OVDD</sub>	Digital Supply Current (0V <sub>DD</sub> = 1.8V)	Sine Input, 1.75mA Mode Sine Input, 3.5mA Mode	•		20.7 40.5	23 44	mA mA
P <sub>DISS</sub>	Power Dissipation	Sine Input, 1.75mA Mode Sine Input, 3.5mA Mode	•		196 231	224 262	mW mW
All Output	Modes	ļ					
P <sub>SLEEP</sub>	Sleep Mode Power				0.5		mW
P <sub>NAP</sub>	Nap Mode Power				9		mW
P <sub>DIFFCLK</sub>		fferential Encode Mode Enabled or Nap or Sleep Modes)			10		mW

## **TIMING CHARACTERISTICS** The $\bullet$ denotes the specifications which apply over the full operating temperature range, otherwise specifications are at T<sub>A</sub> = 25°C. (Note 5)

SYMBOL	PARAMETER	CONDITIONS		MIN	ТҮР	MAX	UNITS
f <sub>S</sub>	Sampling Frequency	(Note 10)	•	1	÷	150	MHz
tL	ENC Low Time (Note 8)	Duty Cycle Stabilizer Off Duty Cycle Stabilizer On	•	3.17 2.0	3.33 3.33	500 500	ns ns
t <sub>H</sub>	ENC High Time (Note 8)	Duty Cycle Stabilizer Off Duty Cycle Stabilizer On	•	3.17 2.0	3.33 3.33	500 500	ns ns
t <sub>AP</sub>	Sample-and-Hold Acquisition Delay Time				0		ns

SYMBOL	PARAMETER	CONDITIONS		MIN	ТҮР	MAX	UNITS
Digital Da	ata Outputs (CMOS Modes: Full C	Data Rate and Double Data Rate)					<u> </u>
t <sub>D</sub>	ENC to Data Delay	C <sub>L</sub> = 5pF (Note 8)		1.1	1.7	3.1	ns
t <sub>C</sub>	ENC to CLKOUT Delay	C <sub>L</sub> = 5pF (Note 8)	•	1	1.4	2.6	ns
t <sub>SKEW</sub>	DATA to CLKOUT Skew	$t_D - t_C$ (Note 8)		0	0.3	0.6	ns
	Pipeline Latency	Full Data Rate Mode Double Data Rate Mode			5.0 5.5		Cycles Cycles
Digital Da	ata Outputs (LVDS Mode)						- <b>-</b>
t <sub>D</sub>	ENC to Data Delay	C <sub>L</sub> = 5pF (Note 8)		1.1	1.8	3.2	ns
t <sub>C</sub>	ENC to CLKOUT Delay	C <sub>L</sub> = 5pF (Note 8)	•	1	1.5	2.7	ns
t <sub>SKEW</sub>	DATA to CLKOUT Skew	$t_D - t_C$ (Note 8)	•	0	0.3	0.6	ns
	Pipeline Latency				5.5		Cycles





## **TIMING CHARACTERISTICS** The $\bullet$ denotes the specifications which apply over the full operating temperature range, otherwise specifications are at T<sub>A</sub> = 25°C. (Note 5)

SYMBOL	PARAMETER	CONDITIONS		MIN	ТҮР	MAX	UNITS
SPI Port T	iming (Note 8)	÷					
t <sub>SCK</sub>	SCK Period	Write Mode Readback Mode, C <sub>SDO</sub> = 20pF, R <sub>PULLUP</sub> = 2k	•	40 250			ns ns
ts	CS to SCK Setup Time		•	5			ns
t <sub>H</sub>	SCK to CS Setup Time		•	5			ns
t <sub>DS</sub>	SDI Setup Time		•	5			ns
t <sub>DH</sub>	SDI Hold Time		•	5			ns
t <sub>DO</sub>	SCK Falling to SDO Valid	Readback Mode, C <sub>SDO</sub> = 20pF, R <sub>PULLUP</sub> = 2k	•			125	ns

**Note 1:** Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. Exposure to any Absolute Maximum Rating condition for extended periods may affect device reliability and lifetime.

**Note 2:** All voltage values are with respect to GND with GND and OGND shorted (unless otherwise noted).

**Note 3:** When these pin voltages are taken below GND or above  $V_{DD}$ , they will be clamped by internal diodes. This product can handle input currents of greater than 100mA below GND or above  $V_{DD}$  without latchup.

**Note 4:** When these pin voltages are taken below GND they will be clamped by internal diodes. When these pin voltages are taken above  $V_{DD}$  they will not be clamped by internal diodes. This product can handle input currents of greater than 100mA below GND without latchup.

**Note 5:**  $V_{DD} = 0V_{DD} = 1.8V$ ,  $f_{SAMPLE} = 150MHz$ , LVDS outputs with internal termination disabled, differential ENC<sup>+</sup>/ENC<sup>-</sup> =  $2V_{P-P}$  sine wave, input range =  $2V_{P-P}$  with differential drive, unless otherwise noted.

**Note 6:** Integral nonlinearity is defined as the deviation of a code from a best fit straight line to the transfer curve. The deviation is measured from the center of the quantization band.

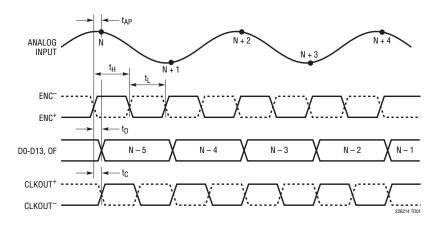
**Note 7:** Offset error is the offset voltage measured from -0.5 LSB when the output code flickers between 00 0000 0000 0000 and 11 1111 1111 1111 1111 in 2's complement output mode.

Note 8: Guaranteed by design, not subject to test.

**Note 9:**  $V_{DD} = 1.8V$ ,  $f_{SAMPLE} = 150MHz$ , ENC<sup>+</sup> = single-ended 1.8V square wave, ENC<sup>-</sup> = 0V, input range =  $2V_{P-P}$  with differential drive, 5pF load on each digital output unless otherwise noted.

Note 10: Recommended operating conditions.

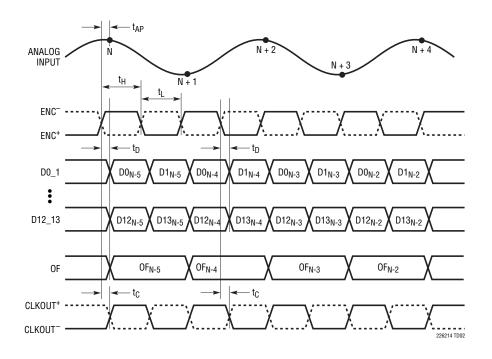
### TIMING DIAGRAMS



Full-Rate CMOS Output Mode Timing All Outputs are Single-Ended and Have CMOS Levels

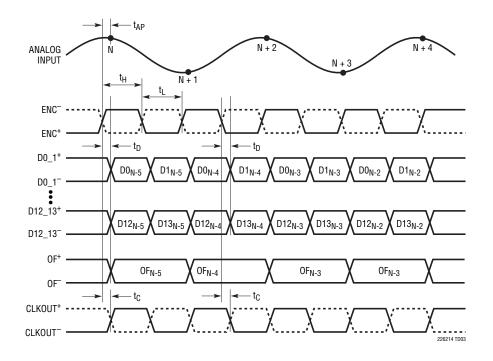


### TIMING DIAGRAMS



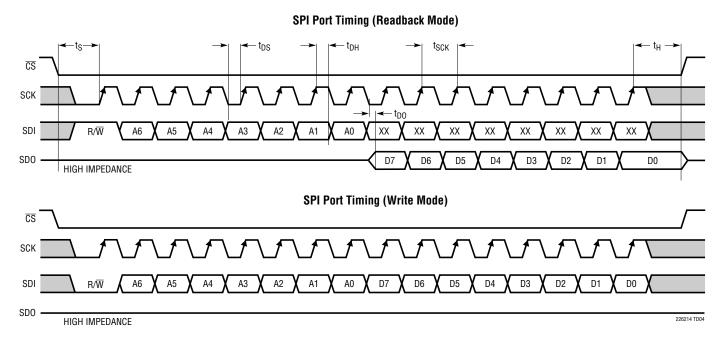
Double Data Rate CMOS Output Mode Timing All Outputs are Single-Ended and Have CMOS Levels

Double Data Rate LVDS Output Mode Timing All Outputs are Differential and Have LVDS Levels

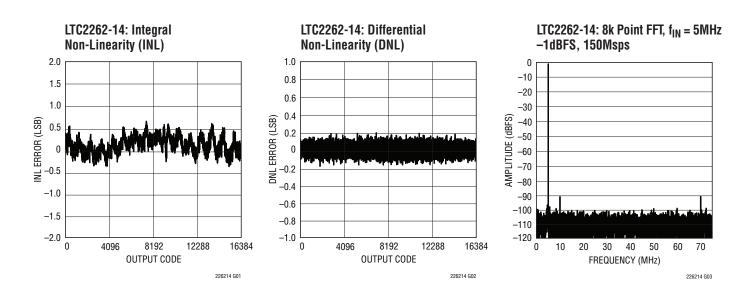




### TIMING DIAGRAMS

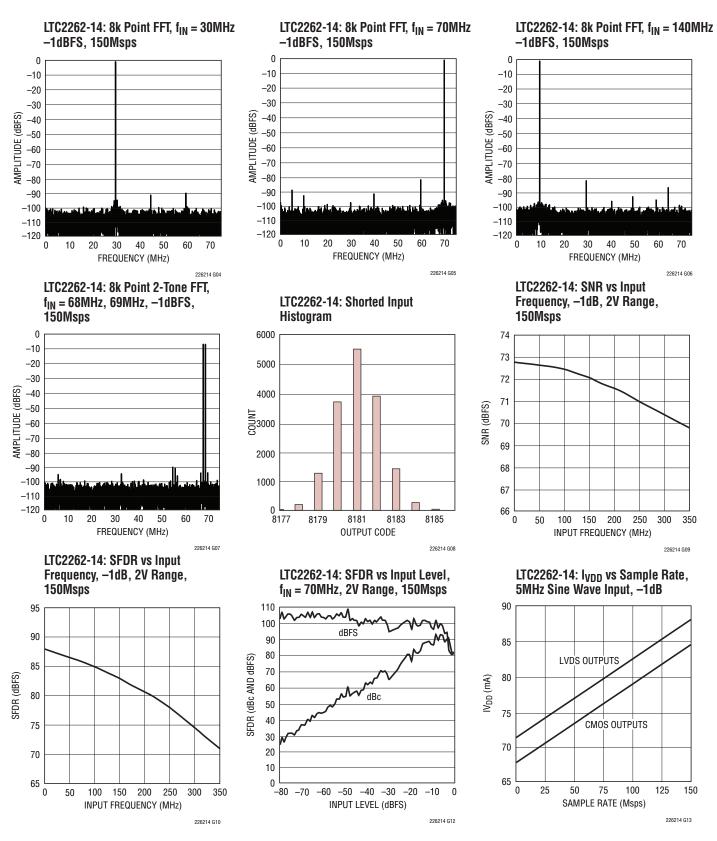


### **TYPICAL PERFORMANCE CHARACTERISTICS**

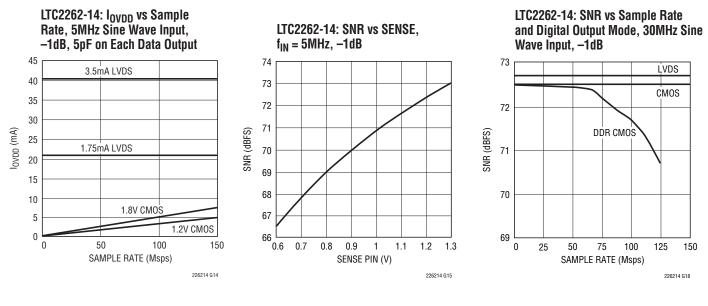




### **TYPICAL PERFORMANCE CHARACTERISTICS**



### TYPICAL PERFORMANCE CHARACTERISTICS



### **PIN FUNCTIONS**

## PINS THAT ARE THE SAME FOR ALL DIGITAL OUTPUT MODES

AIN<sup>+</sup> (Pin 1): Positive Differential Analog Input.

**A**<sub>IN</sub><sup>-</sup> (**Pin 2**): Negative Differential Analog Input.

GND (Pin 3): ADC Power Ground.

**REFH (Pins 4, 5):** ADC High Reference. Bypass to Pins 6, 7 with a  $2.2\mu$ F ceramic capacitor and to ground with a  $0.1\mu$ F ceramic capacitor.

**REFL (Pins 6, 7):** ADC Low Reference. Bypass to Pins 4, 5 with a  $2.2\mu$ F ceramic capacitor and to ground with a 0.1 $\mu$ F ceramic capacitor.

**PAR/SER (Pin 8):** Programming Mode Selection Pin. Connect to ground to enable the serial programming mode.  $\overline{CS}$ , SCK, SDI, SDO become a serial interface that control the A/D operating modes. Connect to V<sub>DD</sub> to enable the parallel programming mode where  $\overline{CS}$ , SCK, SDI become parallel logic inputs that control a reduced set of the A/D operating modes. PAR/SER should be connected directly to ground or the V<sub>DD</sub> of the part and not be driven by a logic signal.

 $V_{DD}$  (Pins 9, 10, 40): 1.8V Analog Power Supply. Bypass to ground with 0.1µF ceramic capacitors. Pins 9 and 10 can share a bypass capacitor.

**ENC<sup>+</sup> (Pin 11):** Encode Input. Conversion starts on the rising edge.

**ENC<sup>-</sup> (Pin 12):** Encode Complement Input. Conversion starts on the falling edge.

**CS** (Pin 13): In serial programming mode, (PAR/ $\overline{SER} = 0V$ ),  $\overline{CS}$  is the serial interface chip select input. When  $\overline{CS}$  is low, SCK is enabled for shifting data on SDI into the mode control registers. In the parallel programming mode (PAR/ $\overline{SER} = V_{DD}$ ),  $\overline{CS}$  controls the clock duty cycle stabilizer. When  $\overline{CS}$  is low, the clock duty cycle stabilizer is turned off. When  $\overline{CS}$  is high, the clock duty cycle stabilizer is turned on.  $\overline{CS}$  can be driven with 1.8V to 3.3V logic.

**SCK (Pin 14):** In serial programming mode, (PAR/ $\overline{\text{SER}}$  = 0V), SCK is the serial interface clock input. In the parallel programming mode (PAR/ $\overline{\text{SER}}$  = V<sub>DD</sub>), SCK controls the digital output mode. When SCK is low, the full-rate CMOS output mode is enabled. When SCK is high, the double data rate LVDS output mode (with 3.5mA output current) is enabled. SCK can be driven with 1.8V to 3.3V logic.



### PIN FUNCTIONS

**SDI (Pin 15):** In serial programming mode, (PAR/ $\overline{SER}$  = 0V), SDI is the serial interface data input. Data on SDI is clocked into the mode control registers on the rising edge of SCK. In the parallel programming mode (PAR/ $\overline{SER}$  =  $V_{DD}$ ), SDI can be used to power down the part. When SDI is low, the part operates normally. When SDI is high, the part enters sleep mode. SDI can be driven with 1.8V to 3.3V logic.

**SDO (Pin 16):** In serial programming mode, (PAR/SER = 0V), SDO is the optional serial interface data output. Data on SDO is read back from the mode control registers and can be latched on the falling edge of SCK. SDO is an open-drain NMOS output that requires an external 2k pull-up resistor to 1.8V-3.3V. If read back from the mode control registers is not needed, the pull-up resistor is not necessary and SDO can be left unconnected. In the parallel programming mode (PAR/SER =  $V_{DD}$ ), SDO is not used and should not be connected.

OGND (Pin 25): Output Driver Ground.

 $OV_{DD}$  (Pin 26): Output Driver Supply. Bypass to ground with a 0.1µF ceramic capacitor.

 $V_{CM}$  (Pin 37): Common Mode Bias Output, Nominally Equal to  $V_{DD}/2.\ V_{CM}$  should be used to bias the common mode of the analog inputs. Bypass to ground with a  $0.1\mu F$  ceramic capacitor.

**V<sub>REF</sub> (Pin 38):** Reference Voltage Output. Bypass to ground with a 1µF ceramic capacitor, nominally 1.25V.

**SENSE (Pin 39):** Reference Programming Pin. Connecting SENSE to V<sub>DD</sub> selects the internal reference and a ±1V input range. Connecting SENSE to ground selects the internal reference and a ±0.5V input range. An external reference between 0.625V and 1.3V applied to SENSE selects an input range of ±0.8 • V<sub>SENSE</sub>.

### FULL-RATE CMOS OUTPUT MODE

All Pins Below Have CMOS Output Levels (OGND to OV<sub>DD</sub>)

**D0 to D13 (Pins 17-24, 29-34):** Digital Outputs. D13 is the MSB.

CLKOUT<sup>-</sup> (Pin 27): Inverted version of CLKOUT<sup>+</sup>.

**CLKOUT**<sup>+</sup> (**Pin 28**): Data Output Clock. The digital outputs normally transition at the same time as the falling edge of CLKOUT<sup>+</sup>. The phase of CLKOUT<sup>+</sup> can also be delayed relative to the digital outputs by programming the mode control registers.

DNC (Pin 35): Do not connect this pin.

**OF (Pin 36):** Over/Under Flow Digital Output. OF is high when an overflow or underflow has occurred.

### DOUBLE DATA RATE CMOS OUTPUT MODE

## All Pins Below Have CMOS Output Levels (OGND to $\ensuremath{\text{OV}_{\text{DD}}}\xspace$

**D0\_1 to D12\_13 (Pins 18, 20, 22, 24, 30, 32, 34):** Double Data Rate Digital Outputs. Two data bits are multiplexed onto each output pin. The even data bits (D0, D2, D4, D6, D8, D10, D12) appear when CLKOUT<sup>+</sup> is low. The odd data bits (D1, D3, D5, D7, D9, D11, D13) appear when CLKOUT<sup>+</sup> is high.

CLKOUT<sup>-</sup> (Pin 27): Inverted version of CLKOUT<sup>+</sup>.

**CLKOUT**<sup>+</sup> (**Pin 28**): Data Output Clock. The digital outputs normally transition at the same time as the falling and rising edges of CLKOUT<sup>+</sup>. The phase of CLKOUT<sup>+</sup> can also be delayed relative to the digital outputs by programming the mode control registers.

DNC (Pins 17, 19, 21, 23, 29, 31, 33, 35): Do not connect these pins.

**OF (Pin 36):** Over/Under Flow Digital Output. OF is high when an overflow or underflow has occurred.

### DOUBLE DATA RATE LVDS OUTPUT MODE

All Pins Below Have LVDS Output Levels. The Output Current Level is Programmable. There is an Optional Internal  $100\Omega$  Termination Resistor Between the Pins of Each LVDS Output Pair.

**D0\_1<sup>-</sup>/D0\_1<sup>+</sup> to D12\_13<sup>-</sup>/D12\_13<sup>+</sup> (Pins 17/18, 19/20, 21/22, 23/24, 29/30, 31/32, 33/34):** Double Data Rate Digital Outputs. Two data bits are multiplexed onto each





V<sub>DD</sub>

### **PIN FUNCTIONS**

differential output pair. The even data bits (D0, D2, D4, D6, D8, D10, D12) appear when CLKOUT+ is low. The odd data bits (D1, D3, D5, D7, D9, D11, D13) appear when CLKOUT+ is high.

CLKOUT-/CLKOUT+ (Pins 27/28): Data Output Clock. The digital outputs normally transition at the same time

FUNCTIONAL BLOCK DIAGRAM

as the falling and rising edges of CLKOUT<sup>+</sup>. The phase of CLKOUT<sup>+</sup> can also be delayed relative to the digital outputs by programming the mode control registers.

OF<sup>-</sup>/OF<sup>+</sup> (Pins 35/36): Over/Under Flow Digital Output. OF<sup>+</sup> is high when an overflow or underflow has occurred.

#### A<sub>IN</sub><sup>†</sup> SECOND PIPELINED ADC STAGE FIFTH PIPELINED INPUT S/H FIRST PIPELINED THIRD PIPELINED FOURTH PIPELINED ADC STAGE ADC STAGE ADC STAGE ADC STAGE AIN Vci $V_{DD}/2$ ÷ VREF 1.25V Ţ Ţ REFERENCE RANGE SELECT

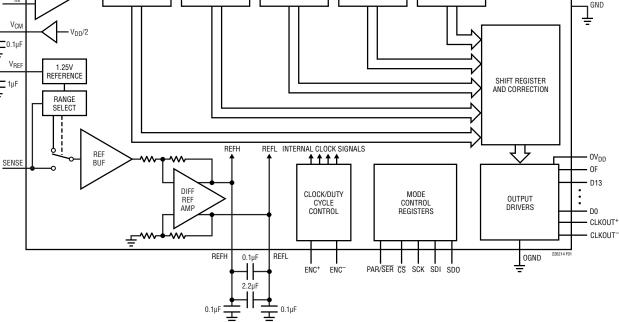


Figure 1. Functional Block Diagram



### **CONVERTER OPERATION**

The LTC2262-14 is a low power 14-bit 150Msps A/D converter that is powered by a single 1.8V supply. The analog inputs should be driven differentially. The encode input can be driven differentially, or single ended for lower power consumption. The digital outputs can be CMOS, double data rate CMOS (to halve the number of output lines), or double data rate LVDS (to reduce digital noise in the system.) Many additional features can be chosen by programming the mode control registers through a serial SPI port. See the Serial Programming Mode section.

#### ANALOG INPUT

The analog input is a differential CMOS sample-and-hold circuit (Figure 2). The inputs should be driven differentially around a common mode voltage set by the V<sub>CM</sub> output pin, which is nominally V<sub>DD</sub>/2. For the 2V input range, the

inputs should swing from  $V_{CM}$  – 0.5V to  $V_{CM}$  + 0.5V. There should be 180° phase difference between the inputs.

#### **INPUT DRIVE CIRCUITS**

#### Input filtering

If possible, there should be an RC lowpass filter right at the analog inputs. This lowpass filter isolates the drive circuitry from the A/D sample-and-hold switching, and also limits wideband noise from the drive circuitry. Figure 3 shows an example of an input RC filter. The RC component values should be chosen based on the application's input frequency.

#### **Transformer Coupled Circuits**

Figure 3 shows the analog input being driven by an RF transformer with a center-tapped secondary. The center tap is biased with  $V_{CM}$ , setting the A/D input at its optimal

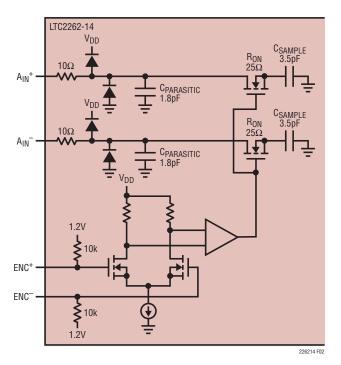


Figure 2. Equivalent Input Circuit

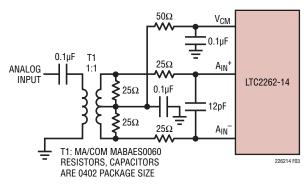


Figure 3. Analog Input Circuit Using a Transformer. Recommended for Input Frequencies from 5MHz to 70MHz

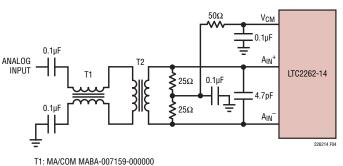


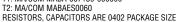
DC level. At higher input frequencies a transmission line balun transformer (Figures 4 to 6) has better balance, resulting in lower A/D distortion.

#### **Amplifier Circuits**

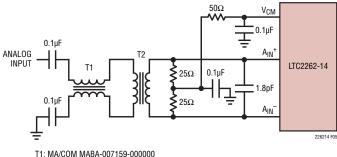
Figure 7 shows the analog input being driven by a high speed differential amplifier. The output of the amplifier is AC coupled to the A/D so the amplifier's output common mode voltage can be optimally set to minimize distortion.

At very high frequencies an RF gain block will often have lower distortion than a differential amplifier. If the gain block is single-ended, then a transformer circuit (Figures 4 to 6) should convert the signal to differential before driving the A/D.









T1: MA/COM MABA-007159-000000 T2: COILCRAFT WBC1-1LB RESISTORS, CAPACITORS ARE 0402 PACKAGE SIZE

#### Figure 5. Recommended Front-End Circuit for Input Frequencies from 170MHz to 270MHz

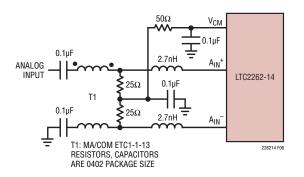


Figure 6. Recommended Front-End Circuit for Input Frequencies Above 270MHz



#### Reference

The LTC2262-14 has an internal 1.25V voltage reference. For a 2V input range using the internal reference, connect SENSE to  $V_{DD}$ . For a 1V input range using the internal reference, connect SENSE to ground. For a 2V input range with an external reference, apply a 1.25V reference voltage to SENSE (Figure 9.)

The input range can be adjusted by applying a voltage to SENSE that is between 0.625V and 1.30V. The input range will then be 1.6  $\bullet$  V\_{SENSE}.

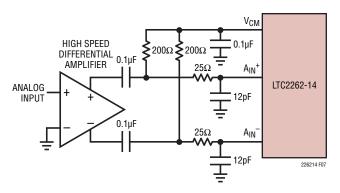


Figure 7. Front-End Circuit Using a High Speed Differential Amplifier

The V<sub>REF</sub>, REFH and REFL pins should be bypassed as shown in Figure 8. The  $0.1\mu$ F capacitor between REFH and REFL should be as close to the pins as possible (not on the back side of the circuit board).

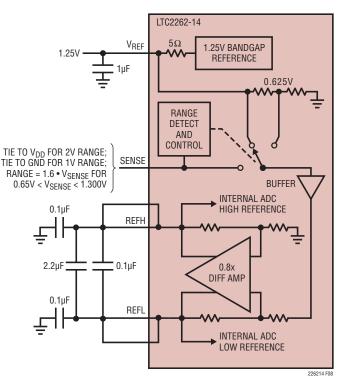


Figure 8. Reference Circuit

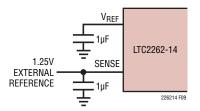


Figure 9. Using an External 1.25V Reference



#### **Encode Input**

The signal quality of the encode inputs strongly affects the A/D noise performance. The encode inputs should be treated as analog signals—do not route them next to digital traces on the circuit board. There are two modes of operation for the encode inputs: the differential encode mode (Figure 10) and the single-ended encode mode (Figure 11).

The differential encode mode is recommended for sinusoidal, PECL or LVDS encode inputs (Figures 12, 13). The encode inputs are internally biased to 1.2V through 10k equivalent resistance. The encode inputs can be taken above  $V_{DD}$  (up to 3.6V), and the common mode range is from 1.1V to 1.6V. In the differential encode mode, ENC<sup>-</sup> should stay at least 200mV above ground to avoid falsely triggering the single-ended encode mode. For good jitter performance ENC<sup>+</sup> and ENC<sup>-</sup> should have fast rise and fall times.

The single-ended encode mode should be used with CMOS encode inputs. To select this mode, ENC<sup>-</sup> is connected to ground and ENC<sup>+</sup> is driven with a square wave encode input. ENC<sup>+</sup> can be taken above  $V_{DD}$  (up to 3.6V) so 1.8V to 3.3V CMOS logic levels can be used. The ENC<sup>+</sup> threshold is 0.9V. For good jitter performance ENC<sup>+</sup> should have fast rise and fall times.

#### **Clock Duty Cycle Stabilizer**

For good performance the encode signal should have a  $50\%(\pm5\%)$  duty cycle. If the optional clock duty cycle stabilizer circuit is enabled, the encode duty cycle can vary from 30% to 70% and the duty cycle stabilizer will maintain a constant 50% internal duty cycle. If the encode signal changes frequency or is turned off, the duty cycle stabilizer circuit requires one hundred clock cycles to lock onto the input clock. The duty cycle stabilizer is enabled by mode control register A2 (serial programming mode), or by  $\overline{CS}$  (parallel programming mode).

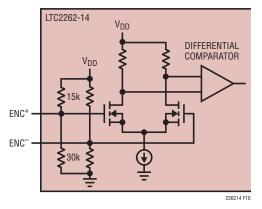


Figure 10. Equivalent Encode Input Circuit for Differential Encode Mode

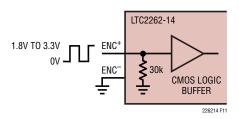
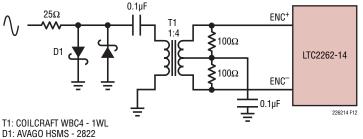


Figure 11. Equivalent Encode Input Circuit for Single-Ended Encode Mode



RESISTORS, CAPACITORS ARE 0402 PACKAGE SIZE

Figure 12. Sinusoidal Encode Drive

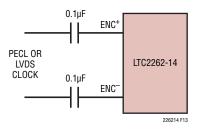


Figure 13. PECL or LVDS Encode Drive

For applications where the sample rate needs to be changed quickly, the clock duty cycle stabilizer can be disabled. If the duty cycle stabilizer is disabled, care should be taken to make the sampling clock have a  $50\%(\pm 5\%)$  duty cycle. The duty cycle stabilizer should not be used below 5Msps.

### **DIGITAL OUTPUTS**

#### **Digital Output Modes**

The LTC2262-14 can operate in three digital output modes: full rate CMOS, double data rate CMOS (to halve the number of output lines), or double data rate LVDS (to reduce digital noise in the system). The output mode is set by mode control register A3 (serial programming mode), or by SCK (parallel programming mode). Note that double data rate CMOS cannot be selected in the parallel programming mode.

#### Full-Rate CMOS Mode

In full-rate CMOS mode the 14 digital outputs (D0-D13), overflow (OF), and the data output clocks (CLKOUT<sup>+</sup>, CLKOUT<sup>-</sup>) have CMOS output levels. The outputs are powered by  $OV_{DD}$  and OGND which are isolated from the A/D core power and ground.  $OV_{DD}$  can range from 1.1V to 1.9V, allowing 1.2V through 1.8V CMOS logic outputs.

For good performance, the digital outputs should drive minimal capacitive loads. If the load capacitance is larger than 10pF a digital buffer should be used.

#### Double Data Rate CMOS Mode

In double data rate CMOS mode, two data bits are multiplexed and output on each data pin. This reduces the number of data lines by seven, simplifying board routing and reducing the number of input pins needed to receive the data. The 7 digital outputs (D0\_1, D2\_3, D4\_5, D6\_7, D8\_9, D10\_11, D12\_13), overflow (OF), and the data output clocks (CLKOUT<sup>+</sup>, CLKOUT<sup>-</sup>) have CMOS output levels. The outputs are powered by  $OV_{DD}$  and OGND which are isolated from the A/D core power and ground.  $OV_{DD}$  can range from 1.1V to 1.9V, allowing 1.2V through 1.8V CMOS logic outputs.

For good performance the digital outputs should drive minimal capacitive loads. If the load capacitance is larger than 10pF a digital buffer should be used.

When using Double Data Rate CMOS at high sample rates the SNR will degrade slightly (see Typical Performance Characteristics section). DDR CMOS is not recommended for sample frequencies above 100Msps.

#### **Double Data Rate LVDS Mode**

In double data rate LVDS mode, two data bits are multiplexed and output on each differential output pair. There are 7 LVDS output pairs ( $D0_1^+/D0_1^-$  through  $D12_13^+/D12_13^-$ ) for the digital output data. Overflow ( $OF^+/OF^-$ ) and the data output clock (CLKOUT<sup>+</sup>/CLKOUT<sup>-</sup>) each have an LVDS output pair.

By default the outputs are standard LVDS levels: 3.5mA output current and a 1.25V output common mode voltage. An external  $100\Omega$  differential termination resistor is required for each LVDS output pair. The termination resistors should be located as close as possible to the LVDS receiver.

The outputs are powered by  $OV_{DD}$  and OGND which are isolated from the A/D core power and ground. In LVDS mode,  $OV_{DD}$  must be 1.8V.

#### Programmable LVDS Output Current

In LVDS mode, the default output driver current is 3.5mA. This current can be adjusted by serially programming mode control register A3. Available current levels are 1.75mA, 2.1mA, 2.5mA, 3mA, 3.5mA, 4mA and 4.5mA.

#### **Optional LVDS Driver Internal Termination**

In most cases using just an external  $100\Omega$  termination resistor will give excellent LVDS signal integrity. In addition, an optional internal  $100\Omega$  termination resistor can be enabled by serially programming mode control register A3. The internal termination helps absorb any reflections caused by imperfect termination at the receiver. When the internal termination is enabled, the output driver current is increased by 1.6x to maintain about the same output voltage swing.

#### **Overflow Bit**

The overflow output bit (OF) outputs a logic high when the analog input is either overranged or underranged. The overflow bit has the same pipeline latency as the data bits.



#### Phase Shifting the Output Clock

In full-rate CMOS mode the data output bits normally change at the same time as the falling edge of CLKOUT<sup>+</sup>, so the rising edge of CLKOUT<sup>+</sup> can be used to latch the output data. In double data rate CMOS and LVDS modes the data output bits normally change at the same time as the falling and rising edges of CLKOUT<sup>+</sup>. To allow adequate setup-and-hold time when latching the data, the CLKOUT<sup>+</sup> signal may need to be phase shifted relative to the data output bits. Most FPGAs have this feature; this is generally the best place to adjust the timing.

The LTC2262-14 can also phase shift the CLKOUT<sup>+</sup>/ CLKOUT<sup>-</sup> signals by serially programming mode control register A2. The output clock can be shifted by 0°, 45°, 90° or 135°. To use the phase shifting feature the clock duty cycle stabilizer must be turned on. Another control register bit can invert the polarity of CLKOUT<sup>+</sup> and CLKOUT<sup>-</sup>, independently of the phase shift. The combination of these two features enables phase shifts of 45° up to 315° (Figure 14).

#### DATA FORMAT

Table 1 shows the relationship between the analog input voltage, the digital data output bits and the overflow bit. By default the output data format is offset binary. The 2's complement format can be selected by serially programming mode control register A4

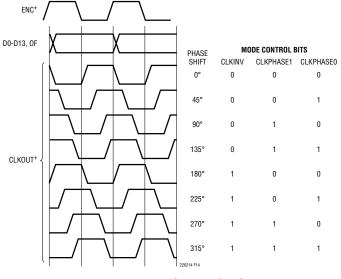


Figure 14. Phase Shifting CLKOUT

A <sub>IN</sub> + – A <sub>IN</sub> <sup>–</sup> (2V Range)	OF	D13-D0 (offset binary)	D13-D0 (2's COMPLEMENT)
>1.000000V	1	11 1111 1111 1111	01 1111 1111 1111
+0.999878V	0	11 1111 1111 1111	01 1111 1111 1111
+0.999756V	0	11 1111 1111 1110	01 1111 1111 1110
+0.000122V	0	10 0000 0000 0001	00 0000 0000 0001
+0.000000V	0	10 0000 0000 0000	00 0000 0000 0000
-0.000122V	0	01 1111 1111 1111	11 1111 1111 1111
-0.000244V	0	01 1111 1111 1110	11 1111 1111 1110
-0.999878V	0	00 0000 0000 0001	10 0000 0000 0001
-1.000000V	0	00 0000 0000 0000	10 0000 0000 0000
≤ <b>-</b> 1.000000V	1	00 0000 0000 0000	10 0000 0000 0000

#### Table 1. Output Codes vs Input Voltage

#### **Digital Output Randomizer**

Interference from the A/D digital outputs is sometimes unavoidable. Digital interference may be from capacitive or inductive coupling or coupling through the ground plane. Even a tiny coupling factor can cause unwanted tones in the ADC output spectrum. By randomizing the digital output before it is transmitted off chip, these unwanted tones can be randomized which reduces the unwanted tone amplitude.

The digital output is "randomized" by applying an exclusive-OR logic operation between the LSB and all other data output bits. To decode, the reverse operation is applied—an exclusive-OR operation is applied between the LSB and all other bits. The LSB, OF and CLKOUT outputs are not affected. The output randomizer is enabled by serially programming mode control register A4.

#### **Alternate Bit Polarity**

Another feature that reduces digital feedback on the circuit board is the alternate bit polarity mode. When this mode is enabled, all of the odd bits (D1, D3, D5, D7, D9, D11, D13) are inverted before the output buffers. The even bits (D0, D2, D4, D6, D8, D10, D12), OF and CLKOUT are not affected. This can reduce digital currents in the circuit board ground plane and reduce digital noise, particularly for very small analog input signals.

When there is a very small signal at the input of the A/D that is centered around midscale, the digital outputs toggle between mostly 1s and mostly 0s. This simultaneous



switching of most of the bits will cause large currents in the ground plane. By inverting every other bit, the alternate bit polarity mode makes half of the bits transition high while half of the bits transition low. To first order, this cancels current flow in the ground plane, reducing the digital noise.

The digital output is decoded at the receiver by inverting the odd bits (D1, D3, D5, D7, D9, D11, D13.) The alternate bit polarity mode is independent of the digital output randomizer—either, both or neither function can be on at the same time. When alternate bit polarity mode is on, the data format is offset binary and the 2's complement control bit has no effect. The alternate bit polarity mode is enabled by serially programming mode control register A4.

#### **Digital Output Test Patterns**

To allow in-circuit testing of the digital interface to the A/D, there are several test modes that force the A/D data outputs (OF, D13-D0) to known values:

All 1s: All outputs are 1

All Os: All outputs are 0

Alternating: Outputs change from all 1s to all 0s on alternating samples

Checkerboard: Outputs change from 101010101010101 to 0101010101010 on alternating samples

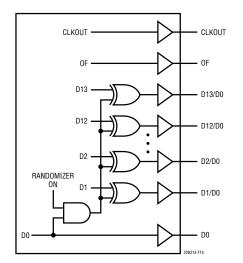


Figure 15. Functional Equivalent of Digital Output Randomizer

The digital output test patterns are enabled by serially programming mode control register A4. When enabled, the test patterns override all other formatting modes: 2's complement, randomizer, alternate-bit-polarity.

#### **Output Disable**

The digital outputs may be disabled by serially programming mode control register A3. All digital outputs including OF and CLKOUT are disabled. The high impedance disabled state is intended for long periods of inactivity—it is too slow to multiplex a data bus between multiple converters at full speed.

#### **Sleep and Nap Modes**

The A/D may be placed in sleep or nap modes to conserve power. In sleep mode the entire A/D converter is powered down, resulting in 0.5mW power consumption. Sleep mode is enabled by mode control register A1 (serial programming mode), or by SDI (parallel programming mode). The amount of time required to recover from sleep mode depends on the size of the bypass capacitors on  $V_{REF}$ , REFH, and REFL. For the suggested values in Figure 8, the A/D will stabilize after 2ms.

In nap mode the A/D core is powered down while the internal reference circuits stay active, allowing faster wake-up than from sleep mode. Recovering from nap

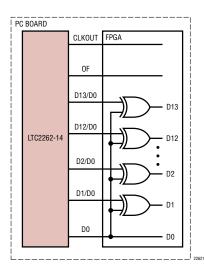


Figure 16. Unrandomizing a Randomized Digital Output Signal





mode requires at least 100 clock cycles. If the application demands very accurate DC settling then an additional 50µs should be allowed so the on-chip references can settle from the slight temperature shift caused by the change in supply current as the A/D leaves nap mode. Nap mode is enabled by mode control register A1 in the serial programming mode.

### **DEVICE PROGRAMMING MODES**

The operating modes of the LTC2262-14 can be programmed by either a parallel interface or a simple serial interface. The serial interface has more flexibility and can program all available modes. The parallel interface is more limited and can only program some of the more commonly used modes.

### Parallel Programming Mode

To use the parallel programming mode, PAR/SER should be tied to  $V_{DD}$ . The  $\overline{CS}$ , SCK and SDI pins are binary logic inputs that set certain operating modes. These pins can be tied to  $V_{DD}$  or ground, or driven by 1.8V, 2.5V or 3.3V CMOS logic. Table 2 shows the modes set by  $\overline{CS}$ , SCK and SDI.

Table 2. Parallel Programming Mode Control Bits (PAR/ $\overline{\text{SER}}$  = V<sub>DD</sub>)

PIN	DESCRIPTION
CS	Clock Duty Cycle Stabilizer Control Bit
	0 = Clock Duty Cycle Stabilizer Off
	1 = Clock Duty Cycle Stabilizer On
SCK	Digital Output Mode Control Bit
	0 = Full-Rate CMOS Output Mode
	1 = Double Data Rate LVDS Output Mode (3.5mA LVDS Current, Internal Termination Off)
SDI	Power Down Control Bit
	0 = Normal Operation
	1 = Sleep Mode

### Serial Programming Mode

To use the serial programming mode, PAR/SER should be tied to ground. The CS, SCK, SDI and SDO pins become a serial interface that program the A/D mode control registers. Data is written to a register with a 16-bit serial word. Data can also be read back from a register to verify its contents.

Serial data transfer starts when  $\overline{\text{CS}}$  is taken low. The data on the SDI pin is latched at the first 16 rising edges of SCK. Any SCK rising edges after the first 16 are ignored. The data transfer ends when  $\overline{\text{CS}}$  is taken high again.

The first bit of the 16-bit input word is the  $R/\overline{W}$  bit. The next seven bits are the address of the register (A6:A0). The final eight bits are the register data (D7:D0).

If the  $R/\overline{W}$  bit is low, the serial data (D7:D0) will be written to the register set by the address bits (A6:A0). If the  $R/\overline{W}$  bit is high, data in the register set by the address bits (A6:A0) will be read back on the SDO pin (see the timing diagrams). During a read back command the register is not updated and data on SDI is ignored.

The SDO pin is an open-drain output that pulls to ground with a 200 $\Omega$  impedance. If register data is read back through SDO, an external 2k pull-up resistor is required. If serial data is only written and read back is not needed, then SDO can be left floating and no pull-up resistor is needed.

Table 3 shows a map of the mode control registers.

### Software Reset

If serial programming is used, the mode control registers should be programmed as soon as possible after the power supplies turn on and are stable. The first serial command must be a software reset which will reset all register data bits to logic 0. To perform a software reset, bit D7 in the reset register is written with a logic 1. After the reset SPI write command is complete, bit D7 is automatically set back to zero.

### **GROUNDING AND BYPASSING**

The LTC2262-14 requires a printed circuit board with a clean unbroken ground plane. A multilayer board with an internal ground plane is recommended. Layout for the printed circuit board should ensure that digital and analog signal lines are separated as much as possible. In particular, care should be taken not to run any digital track alongside an analog signal track or underneath the ADC.

High quality ceramic bypass capacitors should be used at the V<sub>DD</sub>,  $OV_{DD}$ ,  $V_{CM}$ ,  $V_{REF}$ , REFH and REFL pins. Bypass capacitors must be located as close to the pins as possible.



Of particular importance is the 0.1 $\mu$ F capacitor between REFH and REFL. This capacitor should be on the same side of the circuit board as the A/D, and as close to the device as possible (1.5mm or less). Size 0402 ceramic capacitors are recommended. The larger 2.2 $\mu$ F capacitor between REFH and REFL can be somewhat further away. The V<sub>CM</sub> capacitor should be located as close to the pin as possible. To make space for this the capacitor on V<sub>REF</sub> can be further away or on the back of the PC board. The traces connecting the pins and bypass capacitors must be kept short and should be made as wide as possible.

The analog inputs, encode signals, and digital outputs should not be routed next to each other. Ground fill and grounded vias should be used as barriers to isolate these signals from each other.

#### **HEAT TRANSFER**

Most of the heat generated by the LTC2262-14 is transferred from the die through the bottom-side exposed pad and package leads onto the printed circuit board. For good electrical and thermal performance, the exposed pad must be soldered to a large grounded pad on the PC board.

## Table 3. Serial Programming Mode Register Map

D7	D6	D5	D4	D3	D2	D1	D0
RESET	Х	Х	Х	Х	Х	Х	Х
Bit 7	RESET	Software Reset Bit					
	0 = Not Used 1 = Software Rese command The reset register i	t. All Mode Control I is write only	Registers are Rese	t to 00h. This Bit is a	Automatically Set Ba	ack to Zero at the en	d of the SPI writ
Bits 6-0	Unused, Don't Car	e Bits.					
EGISTER A1:	POWER-DOWN REGIS	TER (ADDRESS 01h	)				
D7	D6	D5	D4	D3	D2	D1	D0
Х	Х	Х	Х	Х	Х	PWR0FF1	PWR0FF0
Bits 7-2	Unused, Don't Car	e Bits.	·		·		
	00 = Normal Opera 01 = Nap Mode 10 = Not Used 11 = Sleep Mode TIMING REGISTER (AD						
D7	D6	D5	D4	D3	D2	D1	D0
Х	Х	Х	Х	CLKINV	CLKPHASE1	CLKPHASE0	DCS
Bits 7-4	Unused, Don't Car	e Bits.					
Bit 3		ut Clock Invert Bit JT Polarity (As Shov UT Polarity	vn in the Timing Di	agrams)			
Bits 2-1	01 = CLKOUT+/CL 10 = CLKOUT+/CL	Delay (As Shown in † KOUT <sup>–</sup> Delayed by 4 KOUT <sup>–</sup> Delayed by 9	5° (Clock Period • 0° (Clock Period •	ns) 1/8) 1/4)			
	11 = CLKOUT+/CL Note: If the CLKOU	KOUT <sup>–</sup> Delayed by 1 JT Phase Delay Feat	ure is Used, the Clo	ock Duty Cycle Stabi	ilizer Must Also be T	urned On	

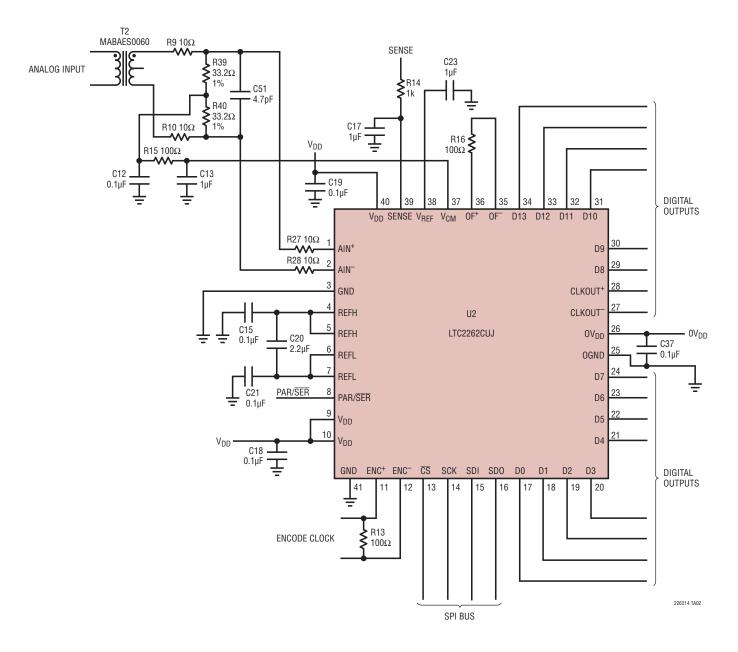


#### **REGISTER A3: OUTPUT MODE REGISTER (ADDRESS 03h)**

D7	D6	D5	D4	D3	D2	D1	D0			
Х	ILVDS2	ILVDS1	ILVDS0	TERMON	OUTOFF	OUTMODE1	OUTMODEC			
t 7	Unused, Don't Car	e Bit.	1			1				
its 6-4	000 = 3.5mA LVDS 001 = 4.0mA LVDS 010 = 4.5mA LVDS 011 = Not Used 100 = 3.0mA LVDS 101 = 2.5mA LVDS 110 = 2.1mA LVDS	DS Output Current Output Driver Curr Output Driver Curr Output Driver Curr Output Driver Curr Output Driver Curr Output Driver Curr S Output Driver Curr	ent ent ent ent ent ent							
it 3	<b>TERMON</b> LVDS Internal Termination Bit 0 = Internal Termination Off 1 = Internal Termination On. LVDS Output Driver Current is 1.6× the Current Set by ILVDS2:ILVDS0									
lit 2	<b>OUTOFF</b> Output Disable Bit 0 = Digital Outputs are Enabled 1 = Digital Outputs are Disabled and Have High Output Impedance									
iits 1-0 Egister A4: I		DS Output Mode Rate LVDS Output N Rate CMOS Output	Mode	ol Bits						
D7	D6	D5	D4	D3	D2	D1	D0			
Х	Х	OUTTEST2	OUTTEST1	OUTTESTO	ABP	RAND	TWOSCOM			
-7.6		I		1 1						
IL /-0	Unused, Don't Car	e Bits.								
Bits 5-3	OUTTEST2:OUTTE 000 = Digital Outp 001 = All Digital Ou 011 = All Digital Ou 101 = Checkerboar 111 = Alternating O	<b>STO</b> Digital ut Test Patterns Off utputs = 0 utputs = 1 rd Output Pattern. C	013-D0 Alternate Be	Bits Between 101 0101 etween 000 0000 000						
its 5-3	OUTTEST2:OUTTE 000 = Digital Outp 001 = All Digital Ou 011 = All Digital Ou 101 = Checkerboau 111 = Alternating O Note: Other Bit Cou	<b>STO</b> Digital ut Test Patterns Off utputs = 0 utputs = 1 rd Output Pattern. OF, I mbinations are not ernate Bit Polarity M olarity Mode Off	)F, D13-D0 Alternate D13-D0 Alternate Be Used	Between 101 0101						
	OUTTEST2:OUTTE000 = Digital Outp001 = All Digital O011 = All Digital O101 = Checkerboar111 = Alternating ONote: Other Bit CorABPAlt0 = Alternate Bit P1 = Alternate Bit P1 = Alternate Bit P0 = Data Output Ra0 = Data Output Ra	<b>STO</b> Digital ut Test Patterns Off utputs = 0 utputs = 1 rd Output Pattern. OF, I mbinations are not ernate Bit Polarity M olarity Mode Off olarity Mode On	DF, D13-D0 Alternate D13-D0 Alternate Be Used Mode Control Bit ter Mode Control Bi	: Between 101 0101 etween 000 0000 001						



### **TYPICAL APPLICATIONS**

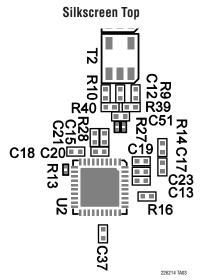


LTC2262 Evaluation Board Schematic

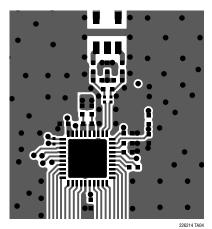




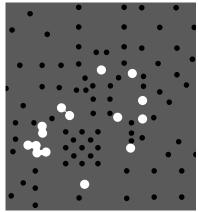
### TYPICAL APPLICATIONS



Top Side

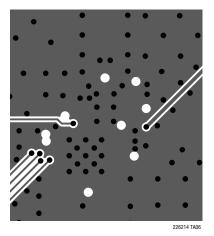


Inner Layer 2 GND

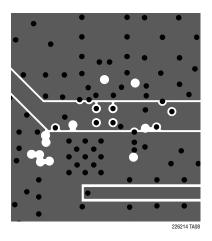


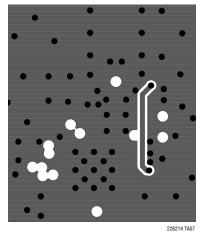
226214 TA04











Inner Layer 4

**Bottom Side** 

